

<b>Notice of References Cited</b>	Application/Control No. 10/702,046	Applicant(s)/Patent Under Reexamination PAN ET AL.	
	Examiner Richard L. Leung	Art Unit 3744	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-1,734,136	11-1929	NATHAN KRAMER	165/184
	B	US-2,737,370	03-1956	MARTIN FRISCH; et. al.	165/134.1
	C	US-4,103,408	08-1978	Joekel, Alfred	29/890.048
	D	US-4,951,739	08-1990	Cates et al.	165/10
	E	US-5,582,246	12-1996	Dinh, Khanh	165/181
	F	US-5,746,269	05-1998	Torii et al.	165/10
	G	US-5,791,149	08-1998	Dean, William G.	62/6
	H	US-6,591,609 B2	07-2003	Kamen et al.	60/526
	I	US-6,691,520 B2	02-2004	Kamoshita et al.	62/6
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 53-132449	11-1978	Japan		B23K 1/12
	O	JP 61-159093	07-1986	Japan	Ito	F28D 20/00
	P	JP 2003-21412	01-2003	Japan	Berkowitz	F25B 9/00
	Q	GB 2382127 A	05-2003	United Kingdom	DANIELS et al.	F17C 13/00
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.